


<b>Search Notes</b> 	<b>Application/Control No.</b> 10577453	<b>Applicant(s)/Patent Under Reexamination</b> VAINIO ET AL.
	<b>Examiner</b> MARCOS BATISTA	<b>Art Unit</b> 2617

SEARCHED			
Class	Subclass	Date	Examiner
455	209	3/11/2008	mb
370	286	3/11/2008	mb

SEARCH NOTES		
Search Notes	Date	Examiner
Consulted with Steve D'Aghosta	3/11/2008	mb
Consulted w/ lab TA Yogesh Aggarwal	3/11/2008	mb
Consulted with Lun-Yi Lao	3/11/2008	mb
Inventor's Name Search	10/22/2008	mb
East Search	10/22/2008	mb
Consulted with Rafael Perez Gutierrez	10/22/2008	mb

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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